BLF6G15L-40BRN

Power LDMOS transistor

Rev. 2 — 12 November 2010

Product data sheet

1. Product profile

1.1 General description

40~W LDMOS power transistor for base station applications at frequencies from 1450 MHz to 1550 MHz.

Table 1. Typical performance

Typical RF performance at $T_{case} = 25$ °C in a class-AB production test circuit.

Mode of operation	f	V_{DS}	P _{L(AV)}	Gp	ηр	ACPR
	(MHz)	(V)	(W)	(dB)	(%)	(dBc)
2-carrier W-CDMA	1476 to 1511	28	2.5	22.0	13.0	-45 <u>[1]</u>

^[1] Test signal: 3GPP test model 1, 64 DPCH; PAR = 7.5 dB at probability of 0.01% on CCDF carrier; carrier spacing 5 MHz.

CAUTION



This device is sensitive to ElectroStatic Discharge (ESD). Therefore care should be taken during transport and handling.

1.2 Features and benefits

- Typical 2-carrier W-CDMA performance at frequencies of 1476 MHz and 1511 MHz, a supply voltage of 28 V and an I_{Dq} of 330 mA:
 - ◆ Average output power = 2.5 W
 - Power gain = 22.0 dB
 - ◆ Efficiency = 13.0 %
 - ◆ ACPR = -45 dBc
- Easy power control
- Integrated ESD protection
- Enhanced ruggedness
- High efficiency
- Excellent thermal stability
- Designed for broadband operation (1450 MHz to 1550 MHz)
- Internally matched for ease of use
- Compliant to Restriction of Hazardous Substances (RoHS) Directive 2002/95/EC.
- Integrated current sense



1.3 Applications

RF power amplifiers for W-CDMA base stations and multi carrier applications in the 1450 MHz to 1550 MHz frequency range

2. Pinning information

Table 2. Pinning

Pin	Description	Simplified outline	Graphic symbol
1	drain		
2	gate	4 5 [1 4,5
3	source		2 6.7
4, 5	sense drain		3 sym126
6, 7	sense gate	6 7	<i>5 5y</i> 20

^[1] Connected to flange.

3. Ordering information

Table 3. Ordering information

Type number	Packag	je	
	Name	Description	Version
BLF6G15L-40BRN	-	flanged ceramic package; 2 mounting holes; 6 leads	SOT1112A

4. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
V_{DS}	drain-source voltage		-	65	V
V_{GS}	gate-source voltage		-0.5	+11	V
V _{GS(sense)}	sense gate-source voltage		-0.5	+9	V
I _D	drain current		-	11	Α
T _{stg}	storage temperature		-65	+150	°C
T _j	junction temperature		-	200	°C

5. Thermal characteristics

Table 5. Thermal characteristics

Symbol	Parameter	Conditions	Тур	Unit
$R_{\text{th(j-case)}}$	thermal resistance from junction to case	$T_{case} = 80 ^{\circ}\text{C}; P_{L} = 2.5 \text{W} (\text{CW})$	1.6	K/W

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6. Characteristics

Table 6. Characteristics

 $T_i = 25$ °C per section; unless otherwise specified

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$V_{(BR)DSS}$	drain-source breakdown voltage	$V_{GS} = 0 \text{ V}; I_D = 0.59 \text{ mA}$	65	-	-	V
$V_{GS(th)}$	gate-source threshold voltage	$V_{DS} = 10 \text{ V}; I_{D} = 59 \text{ mA}$	1.4	1.9	2.4	V
I _{Dq}	quiescent drain current	sense transistor: I_{DS} = 5.1 mA; V_{DS} = 12 V main transistor: V_{DS} = 28 V	280	330	380	mA
I _{DSS}	drain leakage current	$V_{GS} = 0 \text{ V}; V_{DS} = 28 \text{ V}$	-	-	1.4	μΑ
I _{DSX}	drain cut-off current	$V_{GS} = V_{GS(th)} + 3.75 \text{ V};$ $V_{DS} = 10 \text{ V}$	8.8	10	-	Α
I _{GSS}	gate leakage current	$V_{GS} = 11 \text{ V}; V_{DS} = 0 \text{ V}$	-	-	140	nΑ
9 _{fs}	forward transconductance	$V_{DS} = 10 \text{ V}; I_{D} = 2.9 \text{ A}$	2.7	4.3	-	S
R _{DS(on)}	drain-source on-state resistance	$V_{GS} = V_{GS(th)} + 3.75 \text{ V};$ $I_D = 2.06 \text{ A}$	0.09	0.25	0.39	Ω

7. Application information

Table 7. 2-carrier W-CDMA RF performance

Class-AB production test circuit; PAR 7.5 dB at 0.01 % probability on CCDF; 3GPP test model 1; 64 DPCH; f_1 = 1473.4 MHz; f_2 = 1478.4 MHz; f_3 = 1508.4 MHz; f_4 = 1513.4 MHz; RF performance at V_{DS} = 28 V; I_{Dq} = 330 mA; T_{case} = 25 °C; unless otherwise specified.

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$P_{L(AV)}$	average output power		-	2.5	-	W
Gp	power gain	$P_{L(AV)} = 2.5 W$	19.8	22.0	-	dB
RLin	input return loss	$P_{L(AV)} = 2.5 W$	10	15	-	dB
η_{D}	drain efficiency	$P_{L(AV)} = 2.5 \text{ W}$	11	13	-	%
ACPR	adjacent channel power ratio	$P_{L(AV)} = 2.5 W$	-	-45	-40	dBc

Table 8. 1 carrier W-CDMA PAR performance

Class-AB production test circuit; PAR 7.5 dB at 0.01 % probability on CCDF; 3GPP test model 1; 64 DPCH; f_1 = 1510.9 MHz; RF performance at V_{DS} = 28 V; I_{Dq} = 330 mA; T_{case} = 25 °C; unless otherwise specified.

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
PAR _O	output peak-to-average ratio	$P_{L(AV)}$ = 10 W at 0.01 % probability on CCDF	5.3	6.0	-	dB

7.1 Ruggedness in class-AB operation

The BLF6G15L-40BRN is capable of withstanding a load mismatch corresponding to VSWR = 10 :1 through all phases under the following conditions: V_{DS} = 28 V; I_{Dg} = 330 mA; P_{L} = 30 W; f = 1475 MHz (CW).

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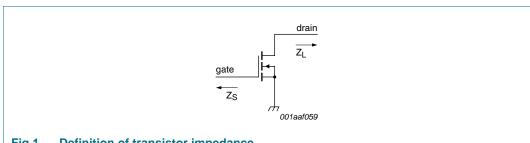
7.2 Impedance information

Typical impedance per section Table 9.

 $I_{Da} = 330 \text{ mA}$; main transistor $V_{DS} = 28 \text{ V}$

-4	20	
f	Z _S [1]	Z _L [1]
(MHz)	(Ω)	(Ω)
1480	3.2 – j6.3	4.6 – j4.5
1510	4.4 – j6.5	4.6 – j4.5

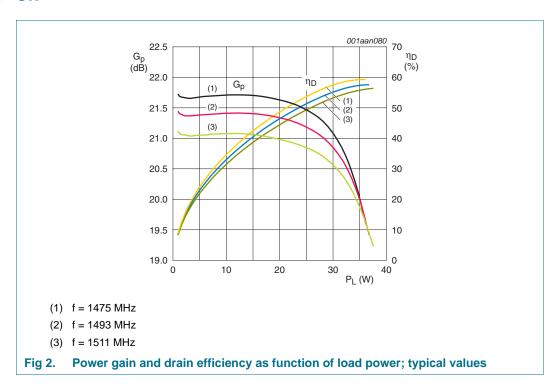
[1] Z_S and Z_L defined in Figure 1.



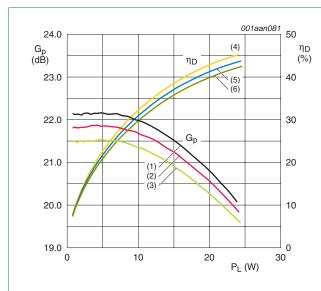
Definition of transistor impedance

7.3 Graphs

7.3.1 CW



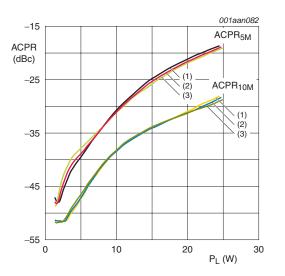
7.3.2 2C-WCDMA (5 MHz spacing)



3GPP, test model 1; 64 DPCH, PAR = 7.5 dB at 0.01 % probability per carrier. 5 MHz carrier spacing.

- (1) f = 1475 MHz
- (2) f = 1493 MHz
- (3) f = 1511 MHz

Fig 3. Power gain and drain efficiency as function of load power; typical values

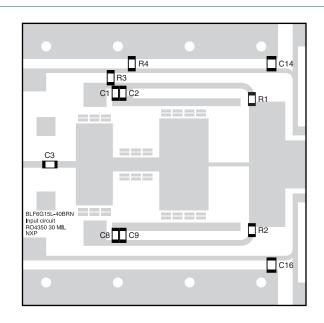


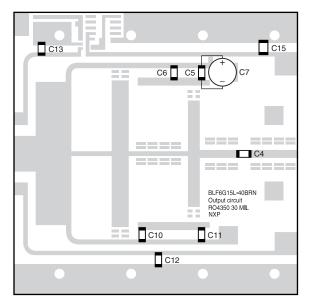
3GPP, test model 1; 64 DPCH, PAR = 7.5 dB at 0.01 % probability per carrier. 5 MHz carrier spacing.

- (1) f = 1475 MHz
- (2) f = 1493 MHz
- (3) f = 1511 MHz

Fig 4. Adjacent channel power ratio as a function of load power; typical values

Test information





014aab103

Printed-Circuit Board (PCB): Rogers RO4350; $\varepsilon_f = 3.5$ F/m; thickness = 0.762 mm; thickness copper plating = 35 μ m. The vias can be as a reference to place components.

The above layout shows the test circuit used to measure the devices in production. A more appropriate application demonstration for specific customer needs can be provided.

See Table 10 for list of components.

Component layout Fig 5.

Table 10. List of components See Figure 5 for component layout.

Component	Description	Value	Remarks
C1, C8	multilayer ceramic chip capacitor	68 pF	<u>[1]</u>
C2, C6, C9	multilayer ceramic chip capacitor	160 pF	<u>[1]</u>
C3, C4	multilayer ceramic chip capacitor	24 pF	[2]
C5, C11	multilayer ceramic chip capacitor	47 pF	<u>[1]</u>
C7	electrolytic capacitor	470 μF; 63 V	
C10	multilayer ceramic chip capacitor	15 pF	<u>[1]</u>
C12	multilayer ceramic chip capacitor	43 pF	<u>[1]</u>
C13	multilayer ceramic chip capacitor	20 pF	<u>[1]</u>
C14, C15	multilayer ceramic chip capacitor	1 μF	Murata 0603
C16	multilayer ceramic chip capacitor	100 pF	
R1, R2	chip resistor	15 Ω	Philips 0603
R3	chip resistor	820 Ω	Philips 0603
R4	chip resistor	1.8 kΩ	Philips 0603

American Technical Ceramics type 100B or capacitor of same quality.

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American Technical Ceramics type 800B or capacitor of same quality.

9. Package outline

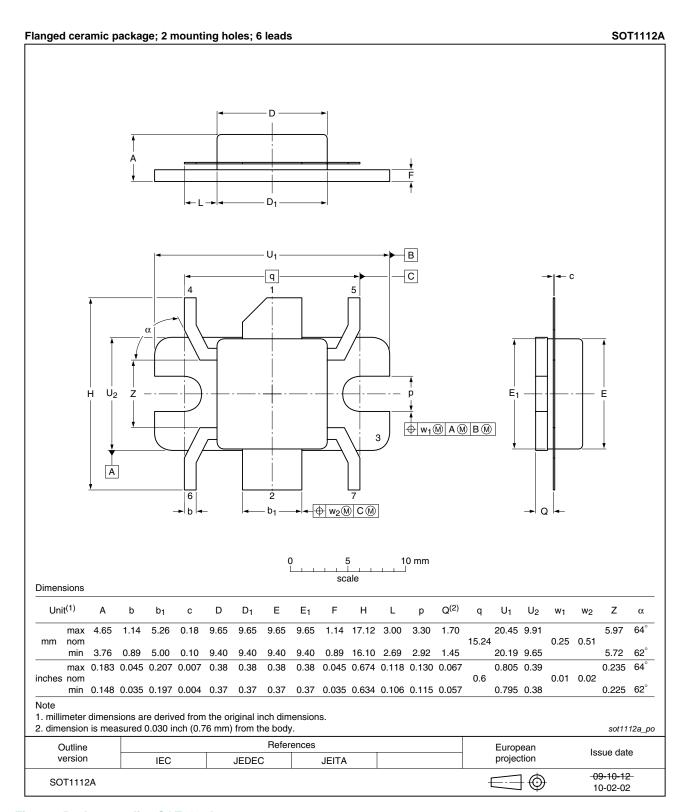


Fig 6. Package outline SOT1112A

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10. Abbreviations

Table 11. Abbreviations

Acronym	Description
3GPP	3rd Generation Partnership Project
CCDF	Complementary Cumulative Distribution Function
LDMOS	Laterally Diffused Metal-Oxide Semiconductor
PAR	Peak-to-Average power Ratio
DPCH	Dedicated Physical Channel
RF	Radio Frequency
VSWR	Voltage Standing-Wave Ratio
W-CDMA	Wideband Code Division Multiple Access

11. Revision history

Table 12. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes	
BLF6G15L-40BRN v.2	20101112	Product data sheet	-	BLF6G15L-40BRN v.1	
Modifications: • Data sheet status changed from Preliminary sheet to Product data					
BLF6G15L-40BRN v.1	20100914	Preliminary data sheet	-	-	

12. Legal information

12.1 Data sheet status

Document status[1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions"
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